

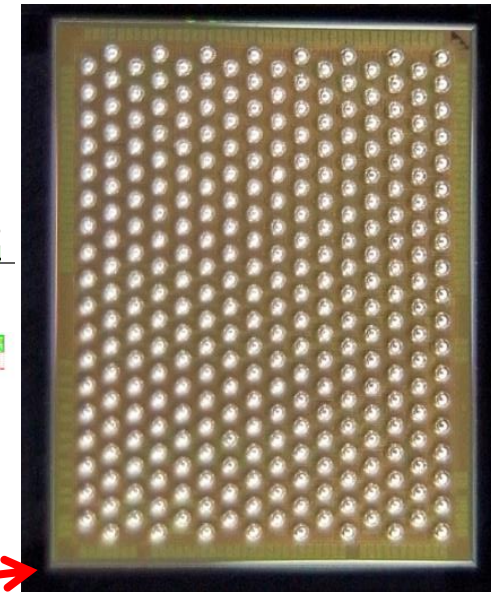
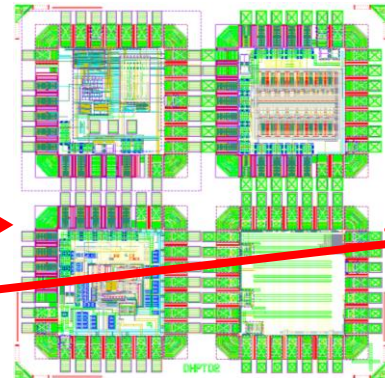
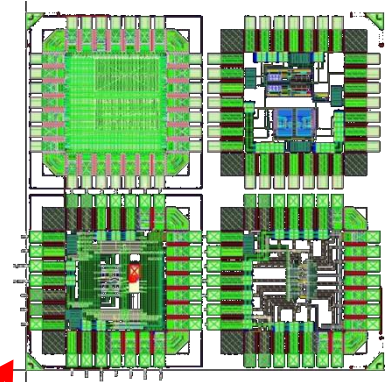
Chip Developments of the Bonn Group

Hans Krüger, Bonn University

- ATLAS Pixel Detector
 - Hybrid pixel sensors
 - FE-I3 (250nm, current pixel detector)
 - FE-I4 (130nm, Insertable B-layer, current upgrade) → done
 - FE-x (65nm, future HL upgrade, RD53 collaboration) → work just started
 - Fully depleted Active CMOS Sensors (DMAPS)
 - Commercial CMOS technology for the sensing layer, monolithic or hybrid → HL upgrade option
- Belle II Pixel Vertex Detector (SuperKEKB e⁺ / e⁻ collider)
 - Digital signal processing on pixel module (65nm, DHP chip) → (almost) done
 - 1.6GHz PLL
 - High speed serial links
 - High density digital signal processing
 - Low power, high density 10 Msps 8-bit ADC
- X-ray imaging (low energy, synchrotron light sources, X-FEL)
 - AGIPD (130nm hybrid pixel detector, XFEL@DESY)
 - New developments: monolithic or hybrid with active CMOS sensors

Projects

- DEPFET Pixel Vertex Detector for BELLE II (2015)
Data handling processor (DHP), mainly digital design, including full custom blocks:
 - PLL (1.6 GHz)
 - High speed serial link (1.6 Gbps)
 - LVDS IO
- „Generic“ (future pixel chips)
 - Low power analog front-end (CSA + discr.)
 - Low power, small area ADC
 - SEU test structures



Chip submissions

- DHPT 0.1, four chiplets, Oct. 2011
- DHPT 0.2, four chiplets, June 2012
- DHPT 1.0
 - 14 mm² MPW
 - C4 bumps

Chip Design Activities – RD53

- Focused on 65nm CMOS technology for HL pixel detector upgrades
- Joint CMS/ATLAS (+CLIC) development
- RD53 collaboration recommended by LHCC June 2013
 - Institutes: 17 (+ 3 new applicants)
 - ATLAS: CERN, Bonn, CPPM, LBNL, LPNHE Paris, NIKHEF, New Mexico, RAL, UC Santa Cruz.
 - CMS: Bari, Bergamo-Pavia, CERN, Fermilab, Padova, Perugia, Pisa, PSI, RAL, Torino.
 - Collaborators: ~100, ~50% chip designers
 - Initial work program covers ~3 years to make foundation for final pixel chips
 - Co-spokes persons: ATLAS: M. Garcia-Sciveres, LBNL. CMS: J. Christiansen, CERN
- RD53 web: www.cern.ch/RD53/

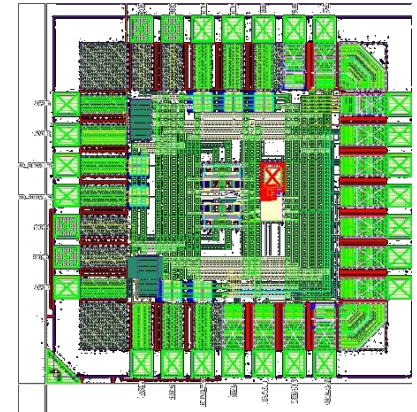
RD53 Working Groups

WG	Domain
WG1	Radiation test/qualification: M. Barbero, CPPM
	<p>Coordinate test and qualification of 65nm for 1Grad TID and 10^{16} neu/cm²</p> <p>Radiation tests and reports.</p> <p>Transistor simulation models after radiation degradation</p> <p>Expertise on radiation effects in 65nm</p>
WG2	Top level: (M. Garcia-sciveres, LBNL)
	<p>Design Methodology/tools for large complex pixel chip</p> <p>Integration of analog in large digital design</p> <p>Design and verification methodology for very large chips.</p> <p>Design methodology for low power design/synthesis.</p> <p>Clock distribution and optimization.</p>
WG3	Simulation/verification framework: T. Hemperek, Bonn
	<p>System Verilog simulation and Verification framework</p> <p>Optimization of global architecture/pixel regions/pixel cells</p>
WG4	I/O : To be started
	<p>Development of rad hard IO cells (and standard cells if required)</p> <p>Standardized interfaces: Control, Readout, etc.</p>
WG5	Analog design / analog front-end: V. Re, Bergamo/Pavia
	<p>Define detailed requirements to analog front-end and digitization</p> <p>Evaluate different analog design approaches for very high radiation environment.</p> <p>Develop analog front-ends</p>
WG6	IP blocks: (J. Christiansen, CERN)
	<p>Definition of required building blocks: RAM, PLL, references , ADC, DAC, power conversion, LDO, ,</p> <p>Distribute design work among institutes</p> <p>Implementation, test, verification, documentation</p>

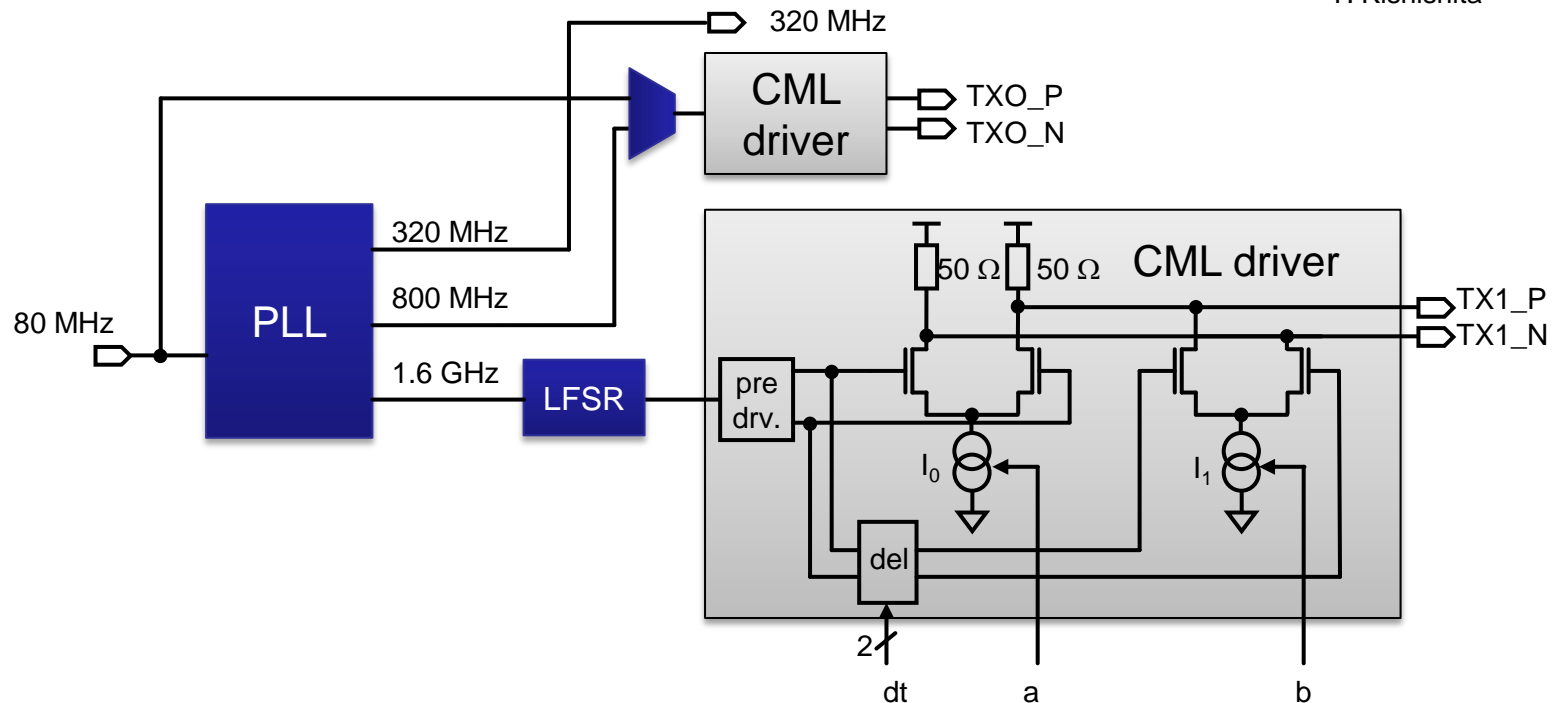
- Backup

PLL & High Speed Link Driver

- PLL
 - 80 MHz reference clock
 - 1.6 GHz, 800MHz & 320 MHz outputs
- Pseudo random bit sequence generator (8 bit LFSR)
- Current mode logic (CML) driver
 - Programmable pre-emphasis (first order FIR filter)
 - Two differential pairs with adj. bias currents (tap weights a, b)
 - Programmable delay dt

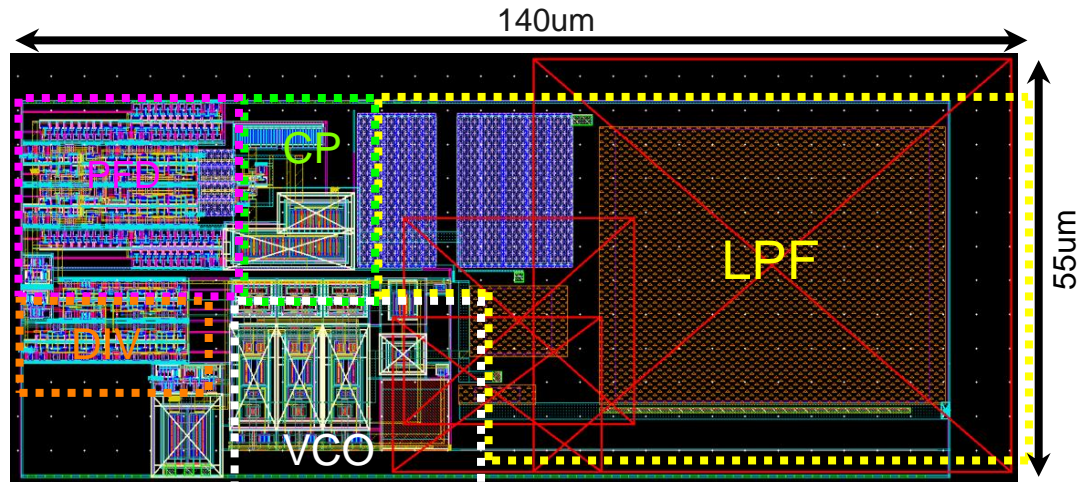


PLL_CML Test Chip,
T. Kishishita

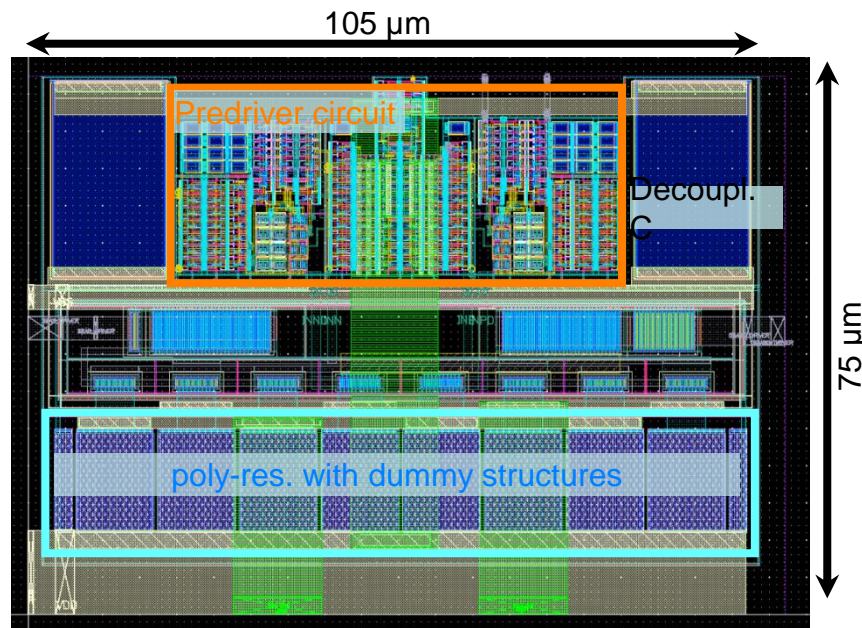


Layouts

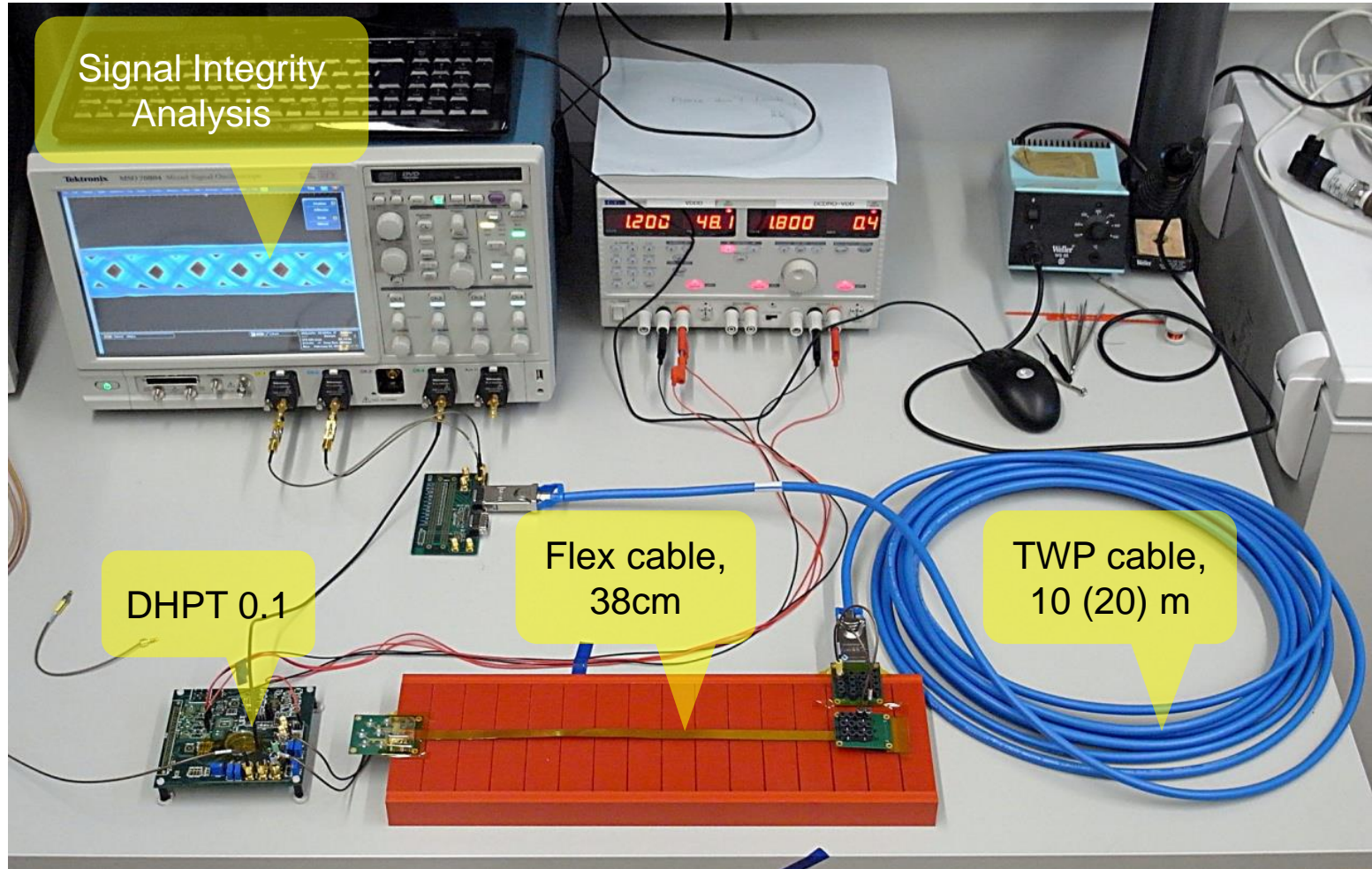
PLL



CML driver

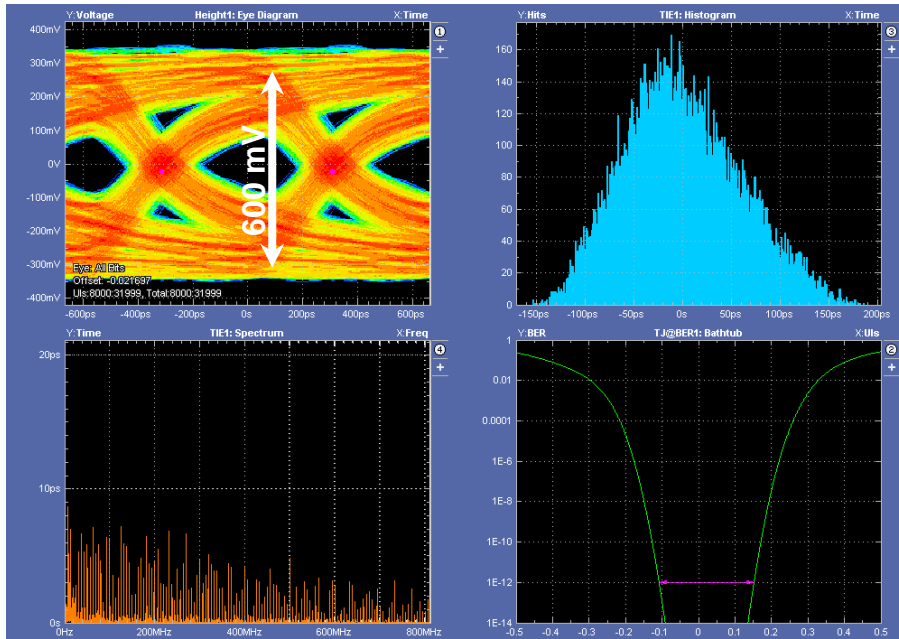


Gbit Link Test Setup

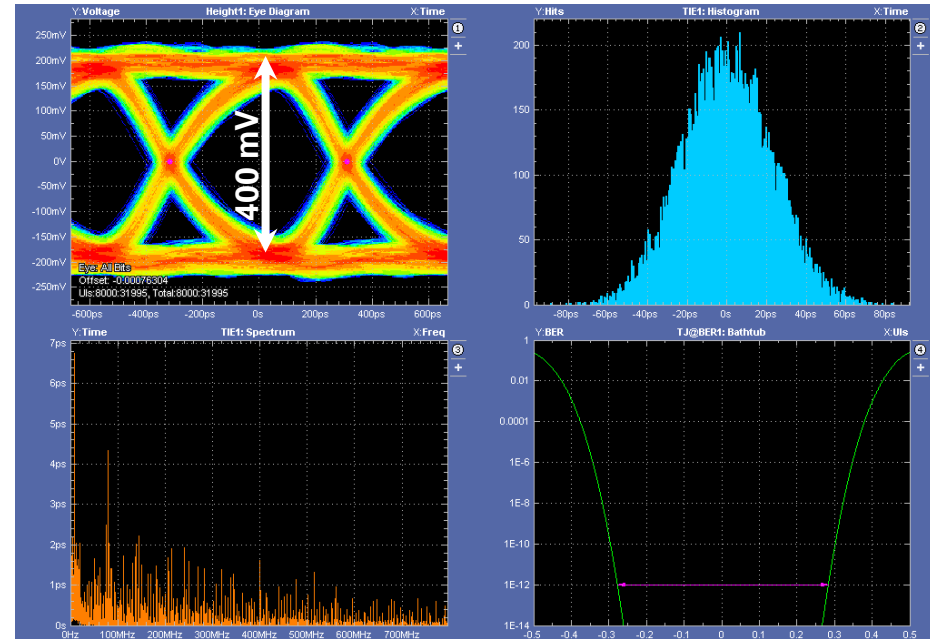


Signal Integrity Analysis

- 1.6 Gbps, 8bit LFSR sequence
- 10m Infiniband cable (LEONI, AWG 26)



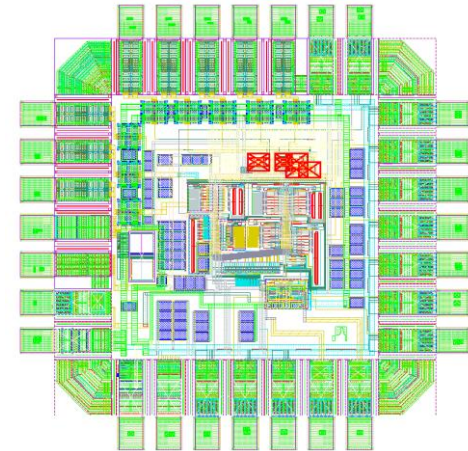
Preemphasis off



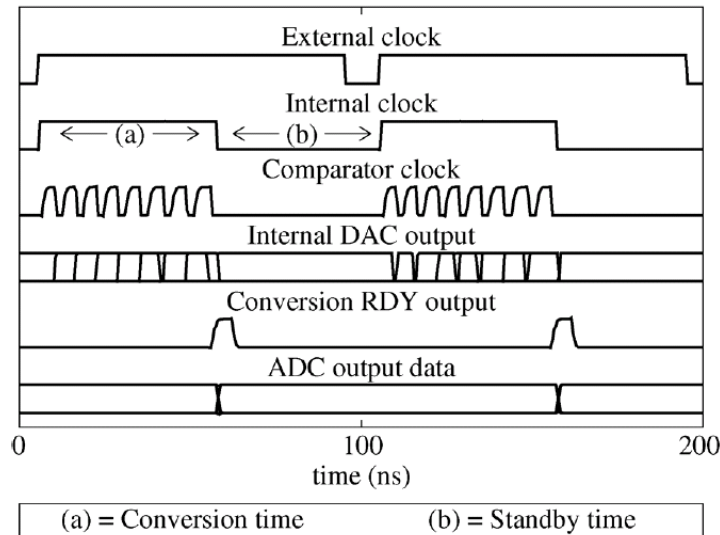
Preemphasis on (600ps, max. I_{boost})

Low Power ADC

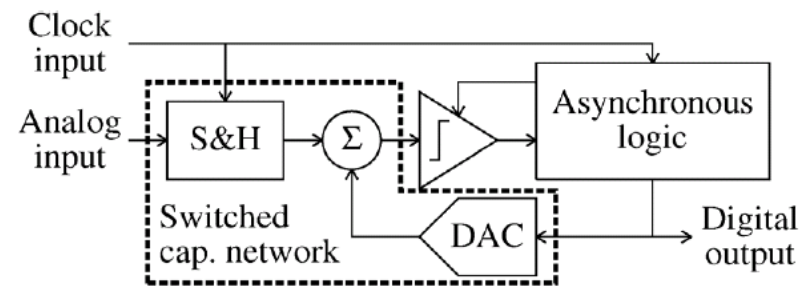
- 8bit ADC
 - 10 Msps
 - Charge redistribution
- Asynchronous operation → low power
 - No clock distribution needed
 - Sample signal triggers digitization sequence
- Serial LVDS data out



T. Hemperek, T. Kisिता



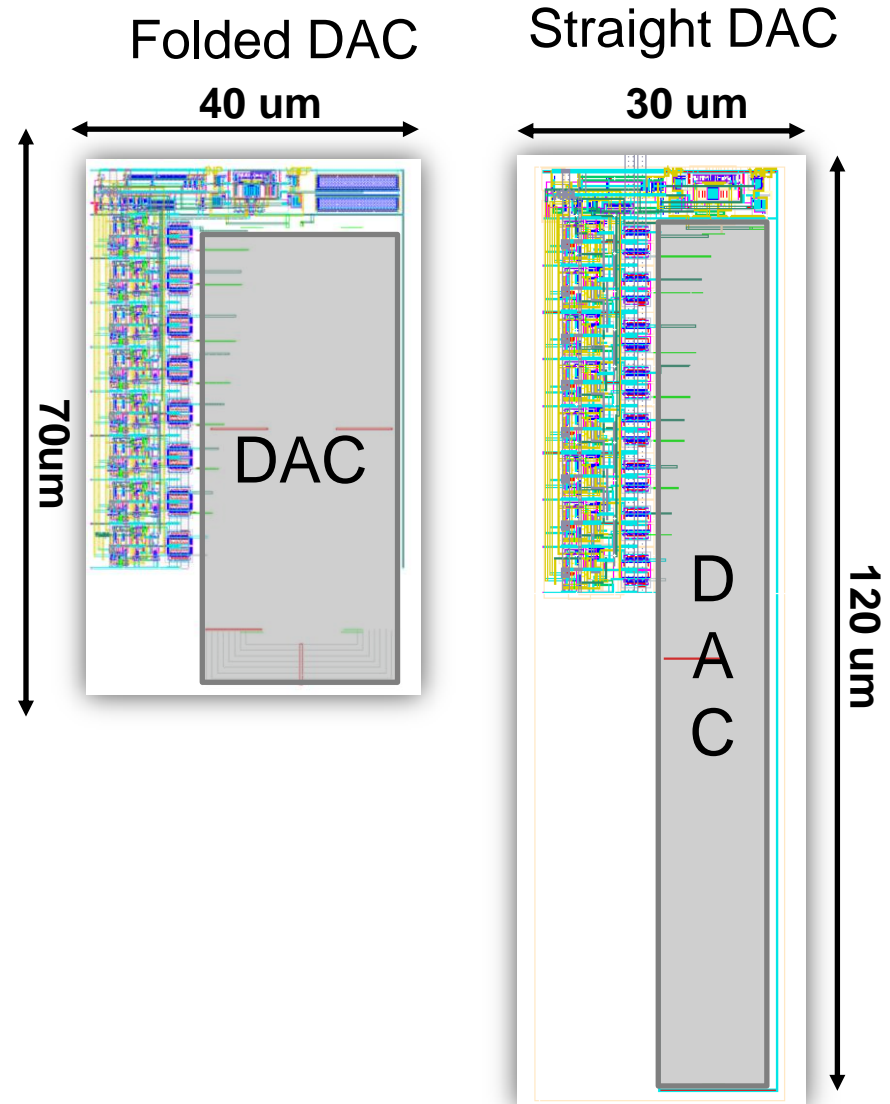
Asynchronous ADC timing



Function Diagram

ADC Layout

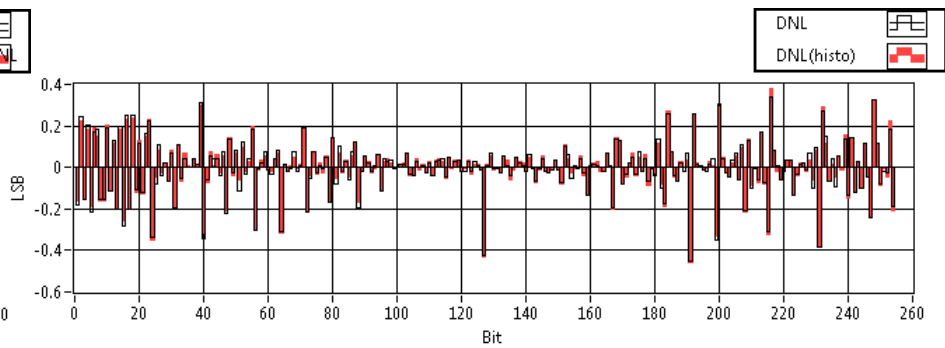
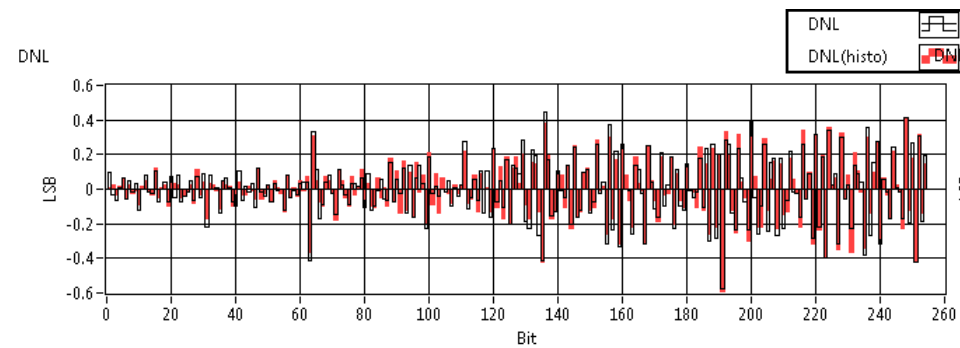
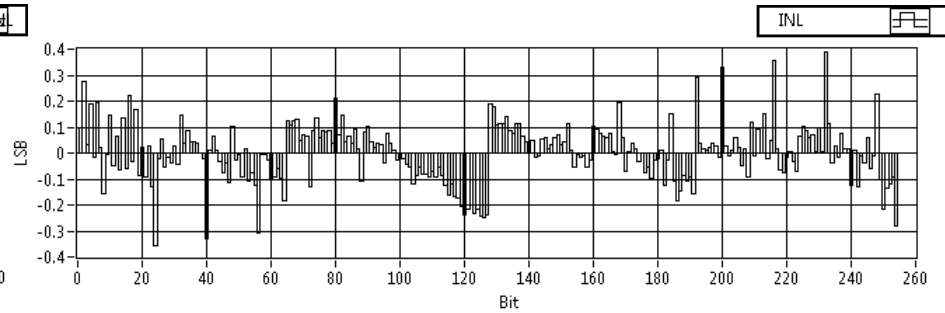
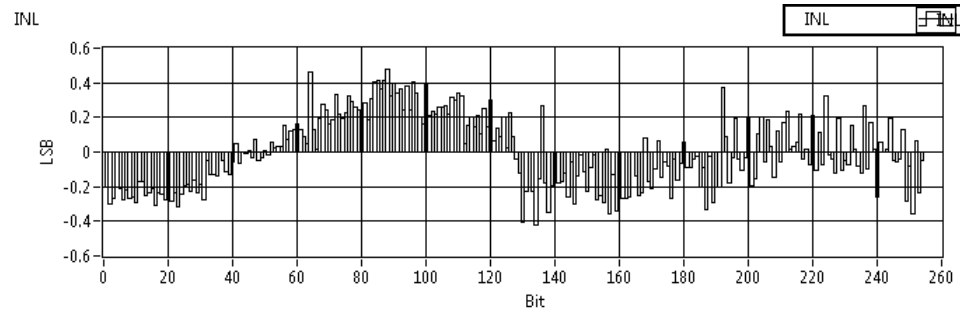
- ADC area dominated by DAC
- Switched capacitor DAC layout critical for DNL performance
- 8 bit → 7 bit: half size



Asynchronous ADC Measurements

Single Ended Mode

Differential Mode



- Measured at 10 MHz sample rate
- Power consumption: ~40uW
- Works up to 12.5 Msps